

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)ATTY DOCKET NO.
00862.109526.INTERNATIONAL APPLICATION
PCT/JP2005/004851

APPLICANT

HIROSHI KAJIWARA

INTERNATIONAL FILING DATE

March 11, 2005

GROUP 2624

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
/E.Y./	JPA	04-207280	7/29/92	JAPAN			Abstract
/E.Y./	JPA	05-191800	7/30/93	JAPAN			Abstract
/E.Y./	JPA	02-309777	12/25/90	JAPAN			Abstract
/E.Y./	JPA	2000-013797	1/14/00	JAPAN			Abstract & corresponding U.S. Patent
/E.Y./	JPA	2003-115765	4/18/03	JAPAN			Abstract
/E.Y./	JPA	2004-056632	2/19/04	JAPAN			Abstract
/E.Y./	JPA	2002-325257	11/8/02	JAPAN			Abstract & corresponding EP & U.S. Patent
/E.Y./	JPA	2000-125304	4/28/00	JAPAN			Abstract
/E.Y./	JPA	2001-112004	4/20/01	JAPAN			Abstract
/E.Y./	JPA	07-095571	4/7/95	JAPAN			Abstract
/E.Y./	JPA	03-006187	1/11/91	JAPAN			Abstract
/E.Y./	JPA	09-149421	6/6/97	JAPAN			Abstract
/E.Y./	JPA	11-275585	10/8/99	JAPAN			Abstract
/E.Y./	JPA	10-023411	1/23/98	JAPAN			Abstract
/E.Y./	JPA	10-126794	5/15/98	JAPAN			Abstract
/E.Y./	JPA	2002-034043	1/31/02	JAPAN			Abstract

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	/Eueng Nan Yeh/	DATE CONSIDERED	07/02/2009
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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/E.Y./	6,396,955	5/28/02	Abe	382	232	
/E.Y./	US 2002/454823 A1	10/24/02	Okada	382	233	2/14/02
	2002/0154823 A1					

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
/E.Y./	EP 1 233 625 A2	8/21/02	EPO			English

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

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